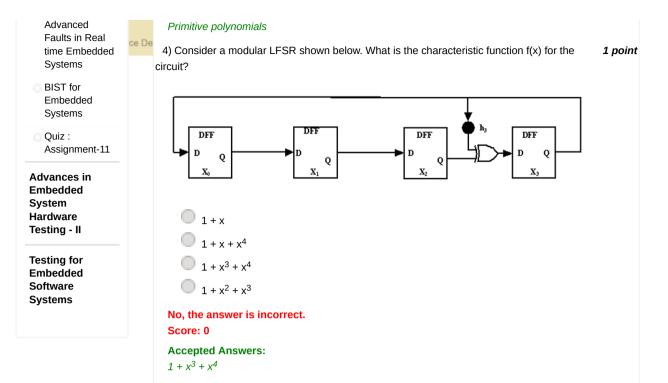
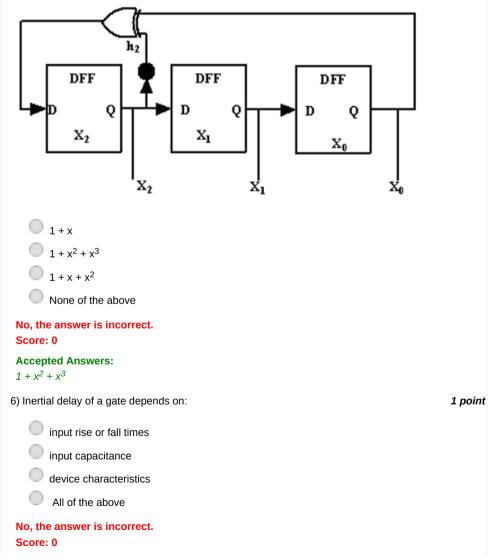


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5) Consider a circuit representation below of a 3-input Linear feedback shift register (LFSR). **1** *point* What is the characteristic polynomial f(x) of the LFSR?



Accepted Answers: All of the above	
7) Which of the following is not a component for Built-in self-test(BIST)? 1 po	int
Hardware test pattern generator	
Output response compactor	
Set and Reset by Shift Register	
Test Controller	
No, the answer is incorrect. Score: 0	
Accepted Answers: Set and Reset by Shift Register	
8) In BIST, which of the following component does the lossy compression of the outputs of the 1 po CUT?	int
Input Mux	
Comparator	
Output response compactor	
No, the answer is incorrect.	
Score: 0	
Accepted Answers: Output response compactor	
9)of BIST generates the test patterns required to sensitize the faults and propagate the 1 po effect to the outputs.	int
Hardware Test Patter Generator	
Output Response Compactor	
Comparator	
Test Controller	
No, the answer is incorrect. Score: 0	
Accepted Answers: Hardware Test Patter Generator	
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